


<b>Search Notes</b> 	<b>Application/Control No.</b> 10595523	<b>Applicant(s)/Patent Under Reexamination</b> NAKAYAMA ET AL.
	<b>Examiner</b> JAE LEE	<b>Art Unit</b> 2823

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SEARCH NOTES		
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EAST search: see attached search histories	07/10/2008	JML
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